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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited. **DESC FORM 193** 

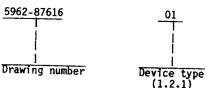
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<ol> <li>SCOPE</li> </ol>
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1.1 <u>Scope</u>. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN

1.2 Part number. The complete part number shall be as shown in the following example:







1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type

Generic number

Circuit function

01

26LS32B

Quad differential line receiver

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

## Outline letter

Case outline

E F 2 D-2 (16-lead, 1/4" x 7/8"), dual-in-line package F-5 (16-lead, 1/4" x 3/8"), flat package C-2 (20-terminal, .350" x .350"), square chip carrier package

1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

Supply voltage ( $V_{CC}$ ) - - - - - - - - - - 4.5 V to 5.5 V Minimum high level input voltage ( $V_{IH}$ ) - - - - - - 2.0 V Maximum low level input voltage ( $V_{IL}$ ) - - - - - - - 0.8 V Ambient temperature range ( $V_{IL}$ ) - - - - - - - - - - - - - - - - - 55°C to +125°C

1/ Must withstand the added Pp due to short circuit test (e.g., Ios).

Z/ When a thermal resistance value for this case is included in MIL-M-38510, appendix C, that value shall supersede the value indicated herein.

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2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

**STANDARD** 

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
  - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Block diagram. The block diagram shall be as specified on figure 2.
  - 3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

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	T	ABLE I. E	lectrical	performance characte	eristics.			
Test	Symbol	       un	Cor -55°C < less other	nditions A < +125°C wise specified	Group A   subgroups	Limits		Uni
Differential input voltage	V <sub>TH</sub>	J	V <sub>OL</sub> or V <sub>OH</sub>   0 V ≤ V <sub>CM</sub> ≤ +5 V		1, 2, 3	T	+100	mV
		 	1/ /	-7 V < VCM < +12 V	1, 2, 3	-200	+200	mV
Input resistance	RIN	  -15 V <u>&lt;</u> V  {One inpu 	CM < +15 \ t ac GND)	2/	1, 2, 3	6.0		kΩ
Input current (under test)	IIN	  V <sub>IN</sub> = +15  Other inp 	γ ut -15 γ	< V <sub>IN</sub> < +15 V	1, 2, 3		+2.3	l mA
Input current (under test)	IIN	  V <sub>IN</sub> = -15  Other inp	γ ut -15 γ	< V <sub>IN</sub> < +15 Y	1, 2, 3		-2.8	l mA
High level output voltage	V <sub>ОН</sub>	VCC = 4.5 VENABLE =	γ 0.8 γ	  I <sub>OH</sub> = -12 mA	1, 2, 3	2.0	İ	V
	   	ΔVIN = +1.	.0 ¥	II <sub>OH</sub> = -1 mA		2.4		٧
Low level output voltage	"	VCC = 4.5	0.8 V	8 V			0.4	٧
		ΔV <sub>IN</sub> = -1.	U ¥	I <sub>OL</sub> = 24 mA			0.5	٧
nable clamp voltage	ν <sub>IC</sub>	I <sub>IN</sub> = -18	mA, V <sub>CC</sub> =	4.5 V	1, 2, 3		-1.5	٧
off-state (high   impedance)   output current	10	V <sub>CC</sub> = 5.5	۷ :	V <sub>OUT</sub> = 2.4 V	1, 2, 3		+50	μА
				V <sub>OUT</sub> = 0.4 V			   -50	μА
igh level input current	I <sub>IH1</sub>	V <sub>CC</sub> = 5.5 V <sub>IN</sub> = 2.7	V V		1, 2, 3		+20	μА
ow level input ! current	IIL	V <sub>CC</sub> = 5.5 V <sub>IN</sub> = 0.4 V	V /		1, 2, 3		-0.36	mA
igh level input   current	I IH2	V <sub>CC</sub> = 5.5 \ V <sub>IN</sub> = 5.5 \	! !		1, 2, 3		+100	μА
e footnotes at end o	f table.				<u> </u>	l	<u>!</u> .	
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Test	Symbol	Con	ditions		  Group A  subgrou		Limits			
	<u> </u> 	-55 C <     unless other	-55°C < TA < +125°C unless otherwise specified				Max	! 		
Output short circuit current 3/	1 <sub>0S</sub>	V <sub>CC</sub> = 5.5 V   V <sub>OUT</sub> = 0 V   \( \delta \text{IN} = +1.0 \text{ V} \)			1, 2,	3   -30	-120     	mA   		
Supply current	I CC	V <sub>CC</sub> = 5.5 V  All V <sub>IN</sub> = GND  outputs disabled			1 1, 2,	3	   70 	l mA		
Input hysteresis	VHYST	V <sub>CC</sub> = 5.0 V			1, 2,	3 65	240	naV		
Open circuit input voltage	V IOC	[   			1, 2,	3 1.5	3.0	٧		
Functional test	] ]	  See 4.3.1c 	· <u>-</u>		7, 8			   		
Propagation delay from input to	lt <sub>PLH</sub>	$R_{11} = 1 k\Omega$	  T <sub>A</sub> = +25°C	4/	   9 	l l	   21 	l ns		
output	IKL2 = 280\Omega   See figures	$ R_{L2}^{\dagger}  = 280\Omega$  See figures 3 and 4	1	<u>5</u> /	9, 10,	111	   26 	 		
Propagation delay from input to	t <sub>PHL</sub>		  T <sub>A</sub> = +25°C 	4/	9	l l	21	ns		
output	! ! !	Î 	 	<u>5</u> /	  9, 10, 1	11  	   26 	[   		
from ENABLE to	l İt <sub>PZH</sub> İ				ZH TA	  T <sub>A</sub> = +25°C 	<u>4</u> /	   9 	   	1   16 
output	   	  -  -	   	<u>5</u> /	9, 10,	11	22	 		
from ENABLE to	l  t <sub>PZL</sub> 	 	  T <sub>A</sub> = +25°C	4/	9	1	   22 	ns		
output	!   	 	   	<u>5</u> /	9, 10,	11	33	   		
ee footnotes at end (	of table			,						
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	TABLE I	• Electrical perfor	mance characte	eristics	- Continue	d.		
Test	  Symbol	Cor	Conditions -55°C < TA < +125°C unless otNerwise specified			Lim	Unit	
	<del>-                                    </del>	unless other	wise specifie	d	subgroups	Min	Max	<u> </u>
Propagation delay from ENABLE to output	t <sub>PHZ</sub>	$ C_{L}  = 5 \text{ pF}$ $ R_{L1}  = 1 \text{ k}\Omega$ $ R_{L2}  = 280\Omega$	T <sub>A</sub> = +25°C	4/	9		   18 	ns
	<u> </u>	See figures 3 and 4		<u>5</u> /	9, 10, 11	   	27	T
Propagation delay from ENABLE to output	t <sub>PLZ</sub>		T <sub>A</sub> = +25°C	4/	9		18	ns
			   	5/	9, 10, 11		27	   
Propagation delay skew	tskew	   tpLH-tpHL  See figures 3 and 4	T <sub>A</sub> = +25°C	4/	   9 		3.0	ns
			 	<u>5</u> /	9, 10, 11		4	
Propagation delay from ENABLE to output		$IR_{L1} = 1 k\Omega \qquad  $	T <sub>A</sub> = +25°C	4/	9		26	ns
		RL2 = 280Ω  See figures 3 and 4 	 	<u>5</u> /	9, 10, 11		39	-
Propagation delay from ENABLE to output	tpZL	 	T <sub>A</sub> = +25°C	4/	9		33	ns
				<u>5</u> /	9, 10, 11		49	-
Propagation delay from ENABLE to output		lK <sub>i1</sub> = 1 kΩ	T <sub>A</sub> = +25°C	<u>4</u> /	9		20	ns
		$R_{L2} = 280\Omega$ T See figures 3 and 4	_	<u>5</u> /	9, 10, 11		30	·
Propagation delay from ENABLE to output	tpLZ	 	T <sub>A</sub> = +25°C	4/	9		20	ns
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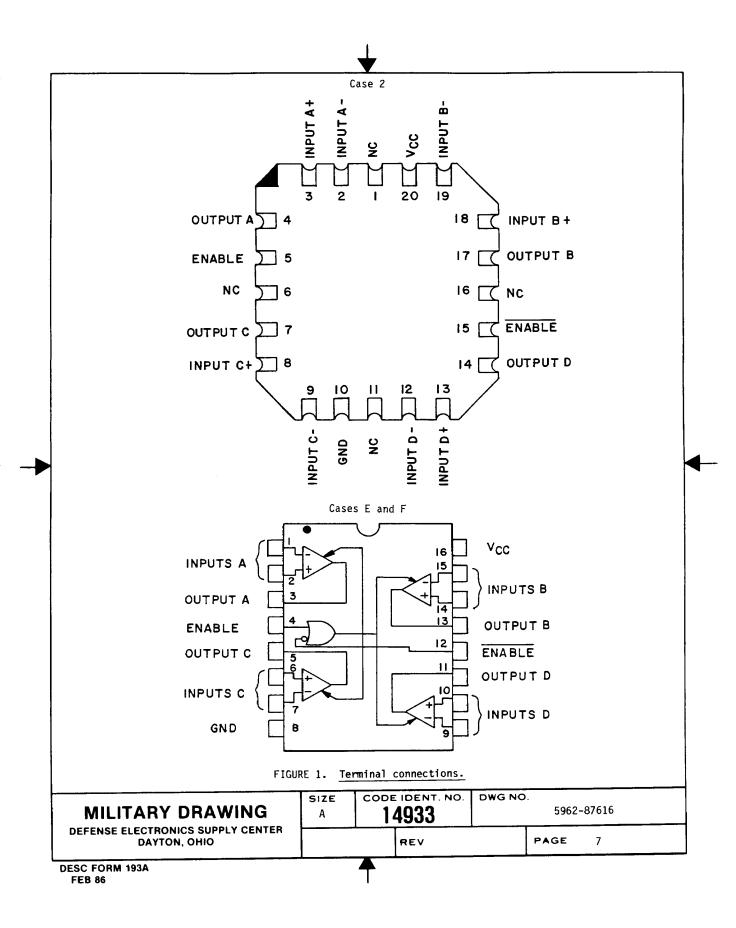
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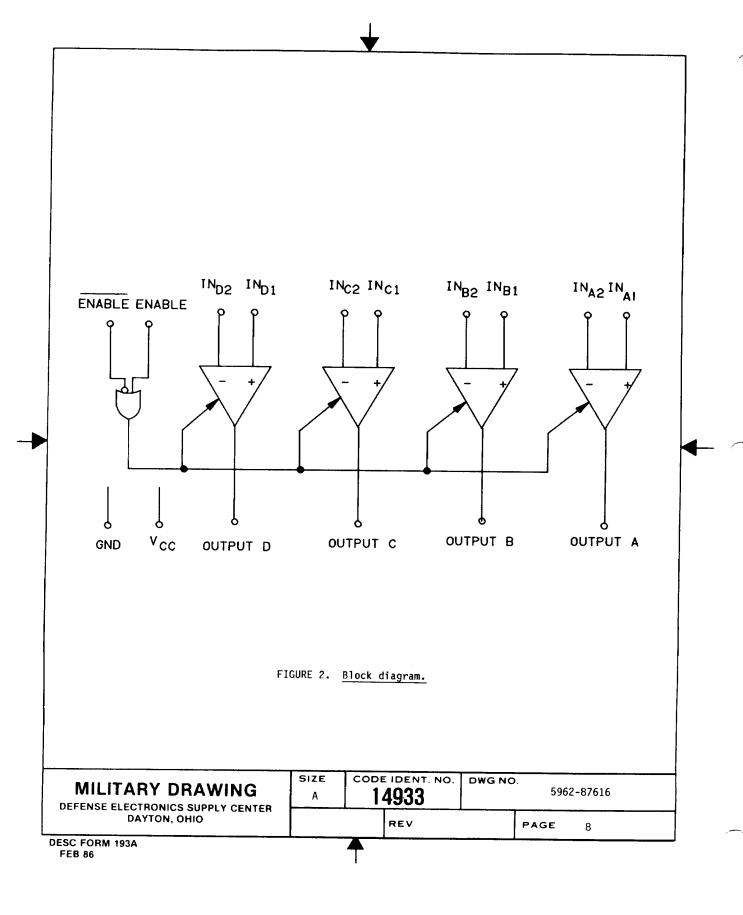
9, 10, 11

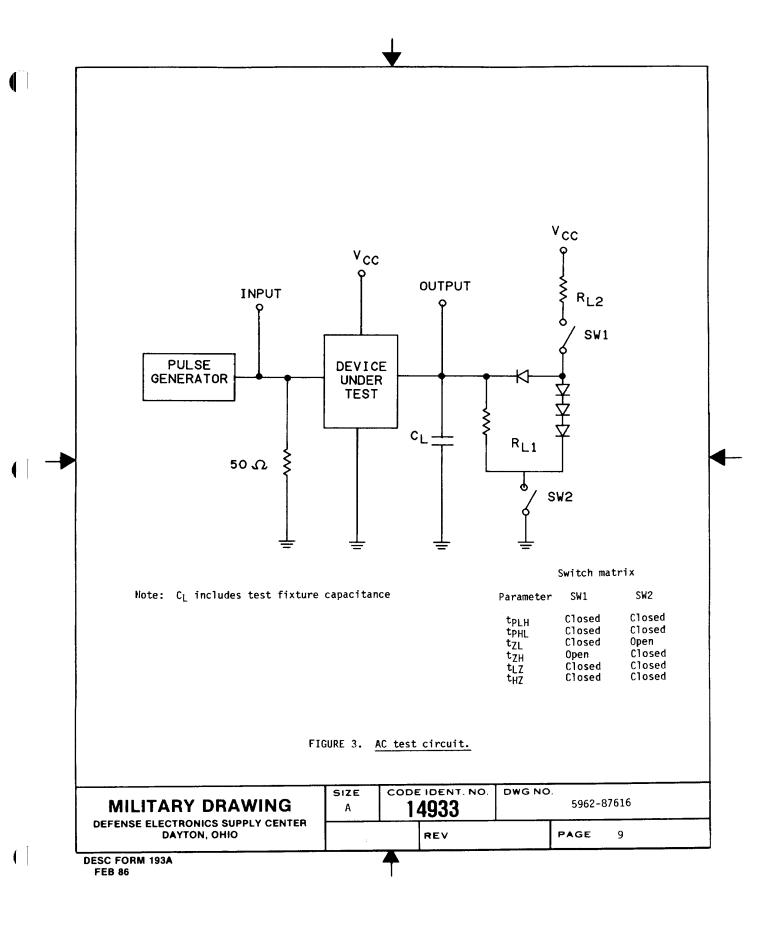
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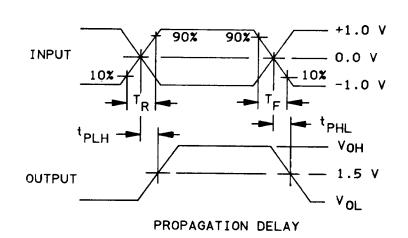
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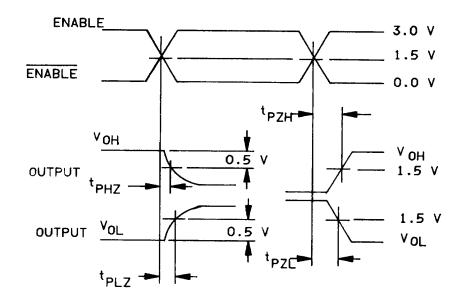
Input voltage is not tested directly due to tester accuracy limitations but is tester correlated. RIN is not directly tested but is correlated. Not more than one output should be shorted at a time. Duration of short circuit test should not exceed one second. V<sub>CC</sub> = 5.0 V. V<sub>CC</sub> = 4.5 V to 5.5 V.









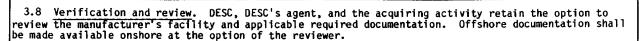


- 1. Pulse generator for all pulses: Rate < 1.0 MHz;  $Z_0$  = 50 ohms;  $t_r \le 2.5$  ns;  $t_f \le 2.5$  ns. 2.  $C_L$  includes probe and jig capacitance. 3. All diodes are 1M916 or 1M3064.

FIGURE 4. Switching time waveforms.

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## 4. QUALITY ASSURANCE PROVISIONS

- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test (method 1015 of MIL-STD-883).
    - (1) Test condition A, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroups 7 and 8 testing shall be sufficient to verify the functional operation of the device.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
      - (1) Test condition A, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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## TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups     (per method     5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters   (method 5004)	1 1*, 2, 3, 7, 8, 9, 10**, 11**
Group A test requirements (method 5005)	1, 2, 3, 7, 8,     9, 10**, 11**
Groups C and D end-point   electrical parameters   (method 5005)	1, 2, 3

PDA applies to subgroup 1.

\*\* Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

## 5. PACKAGING

- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

   Military drawing   part number 	Vendor   CAGE   number 	Yendor     similar part     number <u>1</u> /
5962-8761601EX	34335	AM26LS32B/BEA
   5962-8761601FX	34335	AM26LS32B/BFA
   5962-87616012X 	34335	AM26LS32B/B2C

 $\frac{1}{\text{acquisition.}} \begin{tabular}{ll} \hline \textbf{Caution.} & \textbf{Do not use this number for item} \\ \hline \textbf{acquisition.} & \textbf{Items acquired to this number may not satisfy the performance requirements of this drawing.} \\ \hline \end{tabular}$ 

Vendor CAGE number 34335 Vendor name and address

Advanced Micro Devices, Inc. 901 Thompson Place P. O. Box 3453 Sunnyvale, CA 94088

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